PLEASE STAMP & MAIL SHOWING RECEIPT OF

A 3 PAGE STATEMENT FILED UNDER 37 CFR 1.56, 1.97 and 1.98.

A 2 PAGE Information Disclosure Statement

on Forms 8A & 8B
18 Patents corresponding to the list on the Form 8A

5 Publications corresponding to the list on the Form 8B

All to do with Serial No. 10/804,926 (my file HDI 103)--mailed frm CA on 8/10/2004



PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Khazeni et al.

Atty. Dckt. HDI 103

Serial No.

10/804,926

Examiner: L

Unknown

Filed:

03/19/2004

Grp Art Unit: 2877

For:

Improved Reflectance

Surface Analyzer

Certificate of Mailing

I, Stanley Z, Cole, hereby certify that this paper is being malled first class mail with the U.S. Postal Service with proper postage affixed addressed to the Commissioner for Patents P.O Box 1450, Alexandria, VA 22313-1450 on the date set forth below.

Date: August 10, 2004

Signed

Statement Filed Pursuant To The Duty To Disclose Under 37 CFR § 1.56, §1.97 and §1.98

Honorable Commissioner of Patents and Trademarks:

Pursuant to the duty to disclose under 37 CFR §§1.56, 1.97 and 1.98, Applicants request consideration of this Information Disclosure Statement.

This Information Disclosure Statement is being filed prior to the first Office Action on the merits in the above-identified case. No fee or certificate is therefore required.

Applicants make of record in the above-identified application the prior art listed on the attached form PTO/SB/08A and 8B (2 pages).

A copy of each of the listed patents and the listed publication is attached.

In connection with the submitted art, it is all cited as background information relating to Surface Reflectance Analyzers.

References A, B, C and F have been cited as references directed to prior art Surface Reflectance Analyzers. All other cited references are cited as background technology to this invention.

It is respectfully requested that:

- 1. The Examiner consider completely the cited references in reaching a determination concerning the patentability of the claims in this application;
- 2. The Examiner sign the enclosed PTO form listing the references to evidence that the cited patents and publication have been fully considered by the Patent and Trademark Office during the examination of this application and that the references listed on the attached submission be printed on any patent that issues from this application.

By submitting this Information Disclosure Statement, Applicants make no representation that a search has been made, or the extent of any search, or that more relevant information does not exist.

By submitting this Information Disclosure Statement, Applicants make no representation that the information cited in the Statement is,

or is considered to be, material to patentability as defined in 37 CFR $\S 1.56$ (b).

Notwithstanding any statement by Applicants the Examiner is urged to form his or her own conclusion(s) regarding the relevance of the cited references.

Respectfully submitted,

Stanley Z. Cole

Registration No. 17,654 Applicants Attorney

(650) 941-0887 August 10, 2004

PTC/SBA98A (08-03)
Approved for use through 07/31/2003, OMB 0651-0031
U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE
Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it confains a valid OMB control number.

Substitute for form 1449/PTO

Sheet 1

Examiner

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

	Complete if Known				
	Application Number	10/804,926			
	Filing Date	03/19/04			
	First Named Inventor	Khazeni, K.			
	Art Unit	2877			
	Examiner Name	Unknown			
	Attorney Docket Number	HDI-103			

Examiner Indiais*	No.1	Document Number Number-Kind Code ^{2 # Income}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	Α	^{US-} 6,515,745 B2	02/04/2003	Vurens et al.	See Statement
	В	US- 6,307,627 B1	10/23/2001	Vurens	See Statement
	Ç	US- 6,134,011	10/17/2000	Klien et al.	See Statement
	D	US- 5,835,220 ···	11/10/1998	Kazama et al.	See Statement
	E	^{US-} 5,790,259	08/04/1998	Mizuhata et al.	See Statement
	F	^{US-} 5,726,455	03/10/1998	Vurens	See Statement
	G	US- 5,644,562	07/01/1997	De Groot	See Statement
	Н	US- 5,438,415	08/01/1995	Kazama et al.	See Statement
	J	us- 5,335,066	08/02/1994	Yamada et al.	See Statement
	K	US- 5,311,285	05/10/1994	Oshige et al.	See Statement
	L .,	US- 5,282,217	01/25/1994	Yamazaki	See Statement
	M	US- 5,102,222	04/07/1992	Berger et al.	See Statement
	N	^{US-} 4,908,508	03/13/1990	Dubbeldam	See Statement
	0	^{US-} 4,893,932	01/16/1990	Knollenberg	See Statement
	Р	US- 4,872,758	10/10/1989	Miyazaki et al.	See Statement
	Q	^{US-} 4,681,450	07/21/1987	Azzam	See Statement
	R	^{US-} 4,585,348	04/29/1986	Chastang'et al.	See Statement
***************************************	S	US- 5,517,312	05/14/1996	Finatov	See Statement
	T	US-			

Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date	MENTS Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	T
		Country Code ³ Triumber ⁶ "Kind Code ⁸ (<i>F known</i>)	MM-DD-YYYY	-,,	Or Relevant Figures Appear	
						t
						L
						Ļ

Signature		Considered
	Initial if reference considered, whether or not citation is in conformance with MPEP 609. Dra-	
	nclude copy of this form with next communication to applicant. ¹ Applicant's unique citation of	

Superior seven accounters as more representative or enter serior. Either Office that issued the document, by the two-letter code (WPPC Standard ST.3). * For Japanese patient documents, the indication of the pear of the region of the Emperior must precede the serial nation of the peter discounter. *Viole of documents by the spropriate symbole as indicated on the document under WIPO Standard ST.16 if possible. *Applicant is to place a check mark here if English language Translation is attached.

Date

Translation is estached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USFTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathwring, preparing, and submitting the completed application from to the USFTO. Three will vary depending upon the individual case. Any comments on the smourt of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexanderia, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO; Commissioner for Patenta, P.O. Box 1450, Alexanderia, VA 22313-1450.

PTO/SB/08B (08-03) Approved for use through 07/31/2006, OMB 0651-0031

	te for form 1449/PTO	uction A	a or 1900, no persons a	e required to respond to a collection	of information unless it contains a valid Complete if Known	OMS CORTO RURBOR.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Application Number	10/804,926	*****
				Filing Date	03/19/04	
				First Named Inventor	Khazeni, K.	***************************************
(Use as many sheets as necossary)				Art Unit	2877	
			ecussary)	Examiner Name	Unknown	
Sheet	2	of	2	Attorney Docket Number	HDI-103	,

Examiner	Cite	NON PATENT LITERATURE DOCUMENTS Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of	
initials*	No.1	the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	Т	AZZAM R.M.A. "Ellipsometry" Handbook of Optics: Devices, Measurements & Properties Vol II, 2nd Edition, Bass, M. et al.(eds).	
		McGraw Hill, Inc.: Chapter 27, pp. 27-1 - 27.26 (1995)	
	U	MEEKS, S. et al. "Optical Surface Analysis of the Head-Disk-Interface of Thin Film Disks" Transactions of the ASME, presented Oct 1994, Maui, HI	
	v	BRIGHT, D. et al. "Concentration histogram imaging: a quantitative view of related images" Microscopy: The Key Research Toll, March 1992 pp. 21-28	
	w	KLEIN, D. et al. "Measurements of Thin Film Disks by Surface Reflectance Analysis" SPIE Conference on Surface Characterization for Computer Disks,	7
		Wafers and Flat Panel Displays, San Jose, CA January 1999, Volume 3619, pp. 18 - 26	
	х	Optics, MILES V. KLEIN and THOMAS E. FURTAK, Second Edition, Wiley, pp. 134 - 135	

Examiner	Date
Signature	Considered

CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSIDERED | CONSI